

User's Guide for the Modular Injection System and Sampling Template (M.I.S.S.T)

Froylan Aguirre
class of '18

June 16, 2018

Foreword

The purpose of this guide is to aid future MISST developers and users. This guide will:

- Give a brief overview of MISST system capabilities.
- Provide development advice.
- Outline the project's current state.

I wrote this guide based on my experience and I hope future developers continue to do so.

Part I

The MISST System

Chapter 1

Terminology and High Level Concepts

1.1 Introduction

In this chapter, we will describe MISST system high level behavior. For more details, refer to the Design Guide.

1.2 System Capabilities and Overall Function

The fault injection system was designed as a System on Chip fault injector module that can be added to a prototype for fault tolerance testing. For example, a researcher could observe the behavior of a bus-based micro-processor system prototype after injecting faults into the prototype's peripherals or CPU. The following list outlines the steps of using MISST:

1. Read documentation and download source code.
2. Implement Adapter module for specific case.
3. Test Adapter module compatibility with MISST and target DUT.
4. Once confirmed to function, program FPGA with test setup.
5. Configure MISST registers for desired testing parameters. Refer to Design Guide for register details.
6. Start fault injection campaign, and wait for its end.
7. Collect and analyze data.

The fault injection system injects faults into a device under test (DUT) and samples specified addresses in that DUT's address space. It is important to note that the DUT and fault injection system are implemented on the same die or programmable logic fabric. How the DUT and fault injection system interface is left to the researcher, and their responsibility to implement a module that allows communication of the fault injection system with the DUT and a PC. See chapter 2 for adapter setup details. After the Adapter is completed, the user must configure the fault injection system by setting system registers to appropriate values. These registers control what, how, and when faults are injected and samples are taken. See **Memory Organization** section of Design Guide for more details. Then the fault injection is prompted to start injecting faults. The system samples data from the DUT and sends it to a PC when sampling time has been reached. In between sampling events, MISST injects faults into the DUT. This is repeated until a stop condition is reached. In the next section we will introduce important concepts.

1.3 Concepts and Terminology

A fault can be identified by three characteristics shown in Table 1.1. Between DUT resets, a specified number of faults are injected, and this grouping is called a *set*. After every set, the fault injection system always samples data from the DUT. See Figure 1.1 for a visual of an injected fault.

Table 1.1: Fault Characteristics

Characteristic	Description
Location	Address of fault location in DUT address space.
Time	Time after previous fault or system start (if first fault in a set) measured in DUT clock cycles.
Type	How data is corrupted. Examples: bit flip, additive error, etc

Timeline of a Set

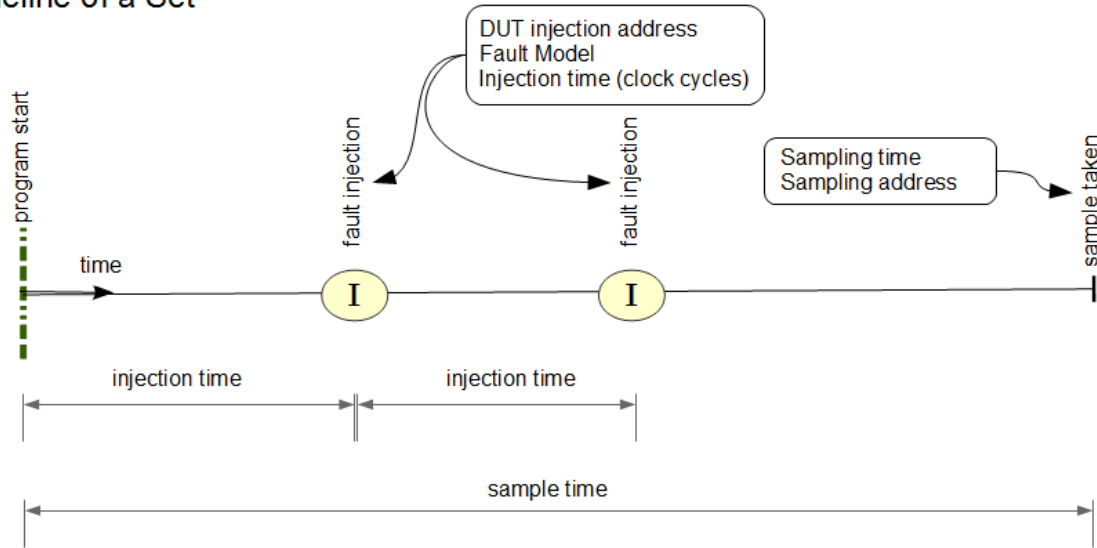


Figure 1.1: Case characteristics.

The fault injection system will normally repeat a cycle of DUT reset, injecting a set of faults, and sampling until a stop condition is reached. We will refer to this cycle as an campaign throughout this document.

1.3.1 Fault Generation

If sets contain multiple faults, and there are multiple sets within a campaign, how are these faults generated? Do faults change between sets or within sets? This section will explain how fault characteristics change between system resets and between injections within sets. The user should keep the following settings in mind when designing a fault injection campaign:

- Initial fault parameter values.
- Number of faults in sets.
- How fault parameters change.

Figure 1.2 shows two ways faults can change within and without sets. In case 1, the same fault is injected multiple times within a set. In case 2, faults change inside sets. For example, case 2 could show that within

sets, the location of the fault changes, but between the sets, another fault characteristic (like timing or fault type) changes.

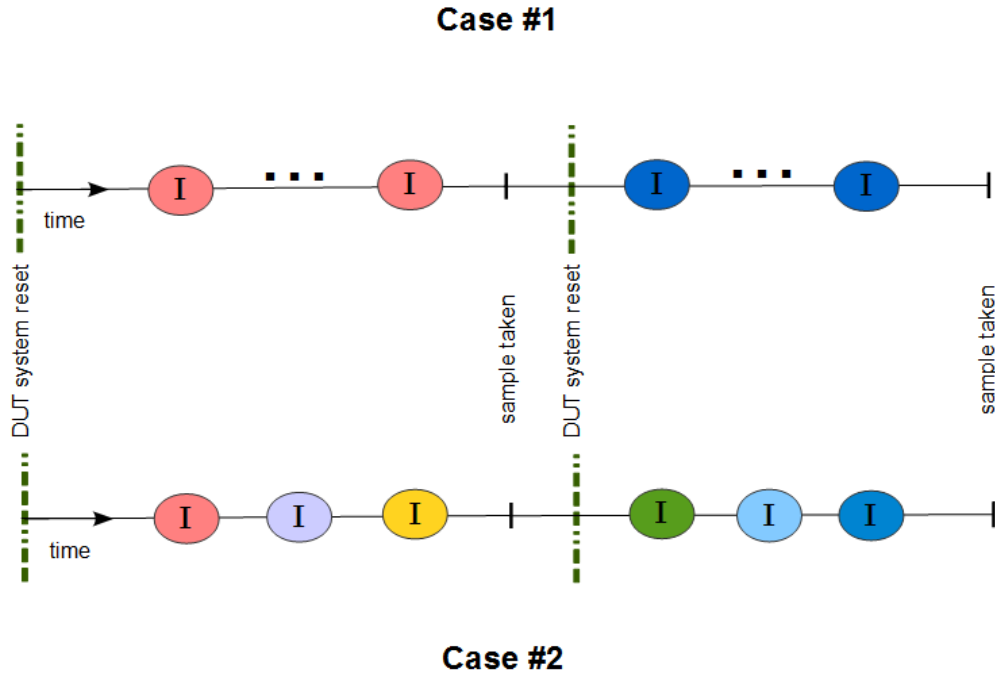


Figure 1.2: Two ways multiple faults can change within and between system resets. Faults of different colors denote faults with different fault parameters. The group of faults between DUT system resets is a fault set.

Faults are generated on the fly meaning that whenever a fault injection occurs, fault characteristics values are generated. The fault injection system does not keep a list of faults, instead it keeps track of initial values, how characteristics change, and acceptable values for each characteristic. Faults can be generated non-randomly or randomly.

Non-random faults are generated by applying an arithmetic operation to a fault characteristic that yields values within a certain range. So every time a new fault is generated, the appropriate fault characteristic is updated by applying an arithmetic operation on that fault characteristic. Hardware checks that the resulting value is within bounds of a specified minimum and maximum.

Randomly generated characteristics can have four different probability distributions. The distributions available are unimodal Gaussian, bimodal Gaussian, uniform uniform, and uniform average.

Remember that multiple fault characteristics can change. How does each fault characteristic change in relation to other fault characteristics? There are two ways to describe how multiple fault characteristics can change relative to each other; parallel and tree-like. In parallel change, multiple fault characteristic change at the same time without being affected by other changing fault parameters. In tree-like change, fault characteristics change in a parallel fashion while another fault characteristic stays constant, but that "constant" fault characteristic can change after a certain number of fault generation requests.

For example, let's say a fault can be characterized by its location and its type, and we are changing both characteristics. In parallel change, every time a new fault is generated (either in case 1 or case 2 of Figure 1.2) both the location and type are updated. In tree-like change, every time a new fault is generated, one of the two fault characteristics will be updated. The other parameter would only be updated after a certain number of updates to the changing parameter. So for a given value for one of the fault characteristic, there will be groups of faults sharing one fault parameter value, but having different values for the other parameters. Figure 1.3 demonstrates the difference between parallel change and tree-like change.

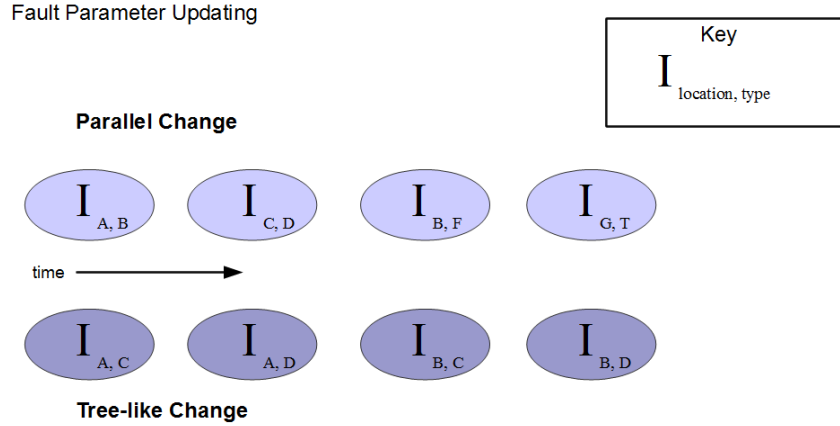


Figure 1.3: Fault Parameter Updating. Shows the difference between parallel and tree-like change.

Randomly Generated Injection Time

Be careful when injection time is configured to be generated randomly. Since injection time can't be predicted in advance, not all faults within a set can be injected before sampling occurs. *All* faults in a set must be injected *before* sampling to avoid injection and sampling at the same time. The MISST system doesn't explicitly enforce each set to have the same number of fault injections before sampling so the MISST system should be configured with that in mind.

Its recommended that if injection time is randomly generated, that sets be limited to only one fault. Make sure to set the appropriate bounds for this injection time so that it occurs before sampling time.

1.3.2 Sampling Data

When a sampling timer timeouts within the Control Unit, MISST samples data from the DUT and sends the data to a PC. The system can sample two locations per set if thats desired. MISST can also be configured to stop a fault campaign based on sampled data. See the Design Guide for more details.

Chapter 2

Adapter Setup

2.1 Introduction

In this chapter we explain how MISST system core communicates with a terminal device (usually a computer) and a DUT. The Adapter module communicates with the fault injection system using a specific protocol. However, how the adapter module communicates with the PC and the DUT is up to the adapter designer.

2.2 Design Goals

Separating the fault injection system's core implementation and external communication module allows the MISST system core to be independent of external communication needs and development board. The fault injection system won't be limited by the development board it's implemented on or available communication hardware.

The adapter module is responsible for routing and controlling signals between the MISST core, a terminal device (usually a PC), and the DUT. A high level diagram of these connections is shown in Figure 2.1.

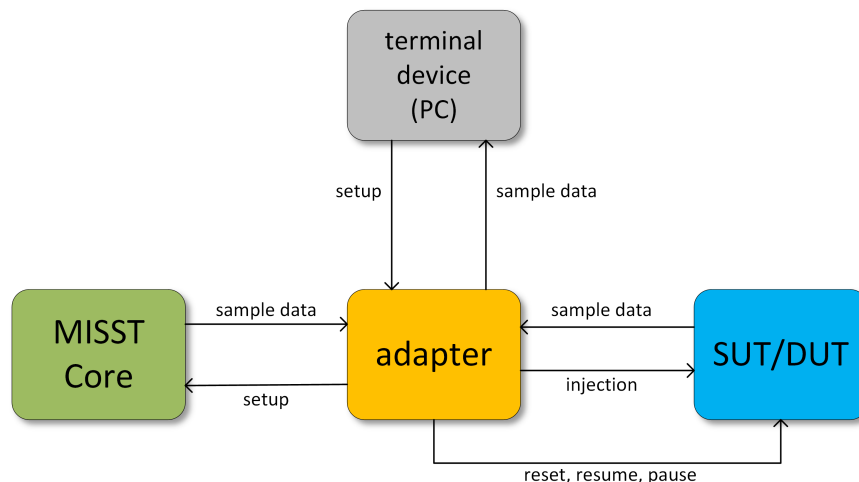


Figure 2.1: High Level Adapter, MISST core, PC, and DUT Interconnect.

2.3 Adapter-Core Communication Protocol

The Adapter-Core Communication Protocol (ACCP) specifies how data is transferred between the adapter module and MISST core. Table 2.1 lists and describes the required ports for the adapter. The only timing

restriction is that the module sending data, be it the adapter module or MISST core, allow sufficient time for the receiver to process incoming data.

Table 2.1: Required Adapter Ports

Port Name	I/O	Description
data_in	input	Data from MISST core.
addr_in	input	Destination address of incoming data.
read_in	input	Writes incoming data at incoming address on rising edge.
campaign_in	input	A high value signals system executing fault campaign.
is_sampling_in	input	A high value indicates system during sampling process.
is_inj_in	input	A high value indicates system during injection process.
samp_inj_in	input	A high value indicates that the value at the injection location is being read for corruption and injection.
data_out	output	Data to MISST core.
addr_out	output	Destination address of outgoing data to MISST.
write_out	output	Rising edge signals write enable for outgoing data at outgoing address to the Control Unit.

The user is free to add additional ports to the adapter as long as the required ports are included. Also note that the register `sys_status` at address `0x0C` (refer to Design Guide's **Memory Organization** section) is implemented in the adapter module. Hence the need for the `sample_in`, `inj_in`, and `campaign_in` input ports.

Part II

Development Tips and Advice

Introduction

Here I will share helpful tips on working with Xilinx Vivado tools, VHDL, and Visio.

2.4 Visio

Visio is useful for creating block diagrams of system components. Visio allows users to create libraries of commonly used objects. I use this functionality to place multiple instances of a module. A useful Visio library is "Integrated Circuit Components". This library contains templates for block diagrams. Access it by following the steps outlined below:

1. Open the "Shapes" left side-bar.
2. Click on "More Shapes" and go to "Engineering", then "Electrical Engineering", and click on "Integrated Circuit Components".
3. This library should now appear under "More Shapes" in the "Shapes" side-bar. You should be able to drag and drop objects from the side-bar to the canvas.

Once a design is ready, you can save the Visio design as a png file to include in documentation.

1. Go to File->Export->Change File Type.
2. Select "PNG Portable Network Graphics" under Graphic File Types. Click "Save As".
3. Select directory to save and name file.
4. Now you should see a window titled "PNG Output Options" as shown in Figure 2.2.
5. Under "Resolution" select "Custom" and type 200 in the text fields with the 'X' between them (these text fields have 96 in Figure 2.2).
6. Under "Size" select Custom.
7. Click ok and the png file should be in the directory you selected earlier.

2.5 VHDL Tips

When planning module implementation, keep the following VHDL rules in mind:

- Signals can only be driven by one source. This means that a signal can be assigned values by combinatorial expressions or sequential expressions, *but not both*. Furthermore, if driven sequentially, only one process at a time can assign values to a signal.
- A process only "runs" or, more accurately, assign values to driven signals when a signal in its sensitivity list changes. Use this to your advantage.
- Conceptualize a process as mini-module with the sensitivity list as inputs and any signals the process drives as outputs. From the point of view of the synthesis tool, the sequential statements in a VHDL process outline an algorithm to map a series of inputs to a series of outputs.
- *NEVER* use the std_logic_arith VHDL library, use numeric_std instead. The std_logic_arith is not approved by the IEEE standardization body [1].
- You can't read the values of entity output ports. Instead, use an internal signal that drives the output port combinatorially, and read the internal signal.

Here is a list of VHDL style choices I followed throughout the project. Files created earlier in the project may not follow some of these style rules.

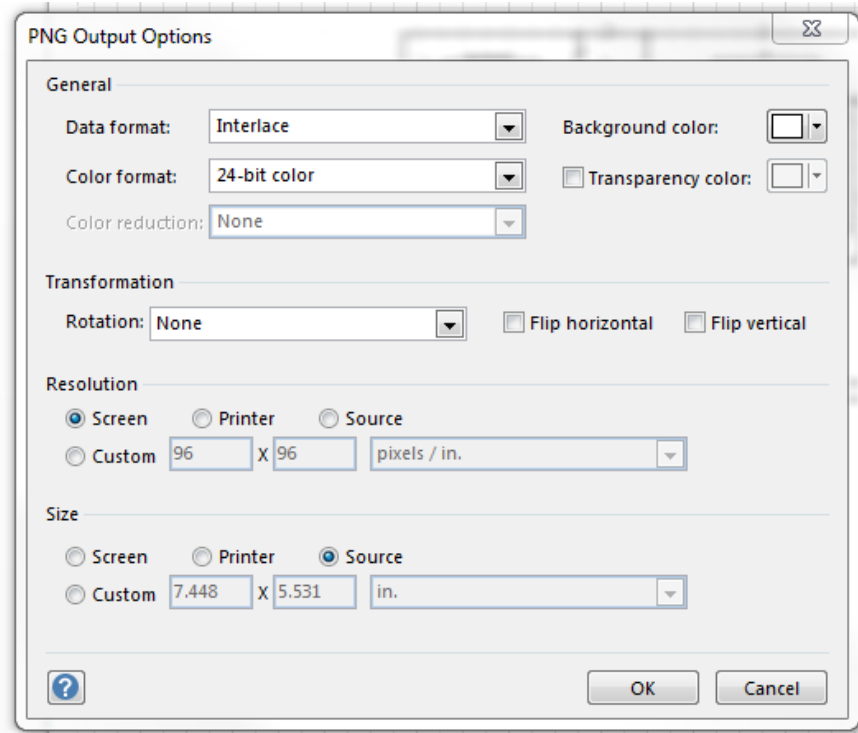


Figure 2.2: PNG Output Options window.

- Internal signals have a "s_" prefix. Early in the project, I used "t_".
- Entity input ports have a "_in" prefix.
- Entity output ports have a "_out" prefix.
- Name processes to describe function.
- Include a reset port on moderately complex modules to initialize and reset registers and internal states.

2.6 Implementation with Xilinx Vivado Tools

I'm assuming that your previous experience with Vivado has been in a digital design course so this section won't be an introduction to Vivado. Instead, I'll share tips that could be helpful in the design and testing process.

Whenever Xilinx tools ask for the board you are using, the PYNQ-Z1 part number is **xc7z020clg400-1**.

2.6.1 Simulation

Testing is an important aspect of development. Try to implement a module's features so that they are not dependent on others. Using this method, features can be tested separately throughout the development process. Before programming the FPGA, test modules with Vivado Simulation. This section will provide tips on making the testing process more efficient.

The source code for the testbench of moderately complex modules will be long, and so will the waveform diagrams. To know what test is running in the waveform window during simulation, create an enumerated type signal whose values correspond to tests in the testbench file. Use the *type* keyword to create an enumeration type. An example architecture section of a testbench is shown below. During the simulation, make sure to add the signal of the enumerated type to the waveform window if not already included. Adding this signal will help you visualize the start and end times of tests.

```

architecture behavior of testbench is
    type TEST_NAME is (TEST_1, TEST_2, TEST_3);
    ...
    signal test_name: TEST_NAME := TEST_1;
    ...
begin
    ...
    stim_proc: process
        ...
        test_name <= TEST_2;
        ...
        test_name <= TEST_3;
        ...
        wait;
    end process;
end;

```

Be aware that in the waveform window you can change the colors of each waveform. You can also create dividers by right clicking in the name column of signal names and selecting the "New Divider" option. Figure 2.3 shows an example of a waveform window.

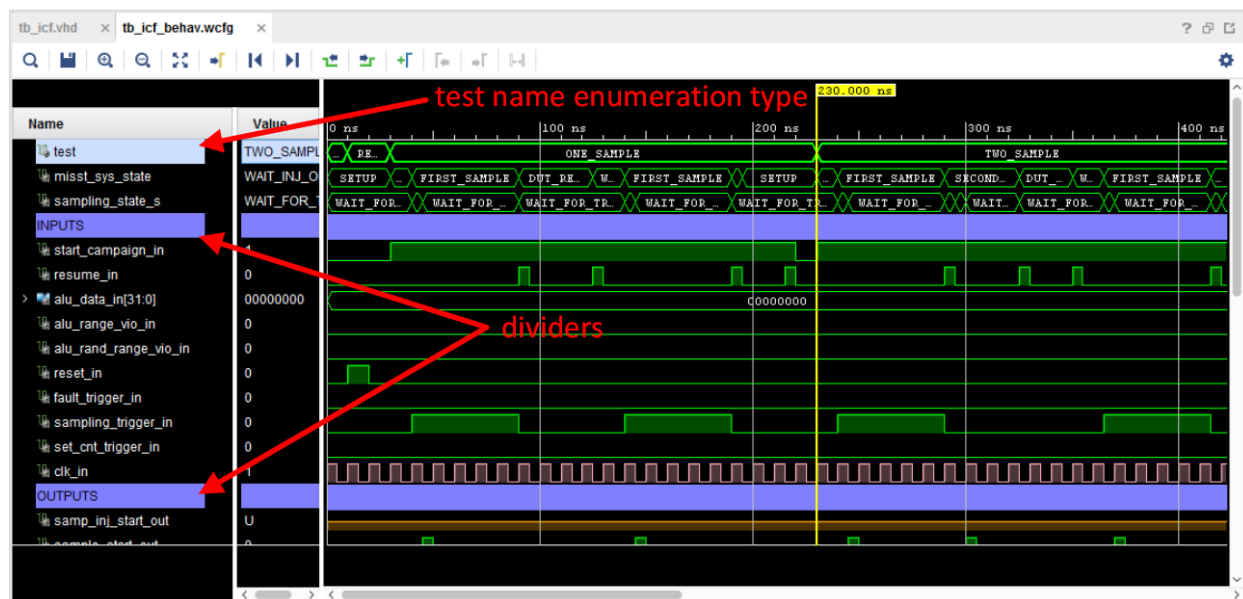


Figure 2.3: Waveform Window Example.

2.6.2 Creating AXI Peripheral

You must create an AXI slave peripheral IP to use in the overall system block design in section 2.6.3. I refer you to chapter 3 of [5]. Start at the beginning of the chapter and when you arrive to step 3 on page 23, continue the steps for "Create a new AXI4 peripheral". For step 5, do not include interrupts. For step 7, select "Edit IP" to add Adapter-Core Communication Protocol logic to the AXI slave (see section 2.3 for protocol requirements).

In the template generated by Vivado, do not heavily modify the AXI protocol logic unless you know what you are doing. To avoid confusion between user code and AXI code, implement your code where comments suggest you do so. For example, you should add any combinatorial logic between the comments below.

The SDK will create a header file that provides read and write functions to an AXI slave peripheral. If we have an AXI slave called IO_Bridge, then the write and read functions will be implemented in header file io_bridge.h. The read and write functions are shown below.

```
#include "io_bridge.h"

// write 0x01 to AXI slave 0 at register 0
IO_BRIDGE_mWriteReg(XPAR_IO_BRIDGE_0_S00_AXI_BASEADDR, IO_BRIDGE_S00_AXI_SLV_REG0_OFFSET, 0x00000001);

// read register 3 from AXI slave 0 and save in unsigned integer variable axi_data
axi_data = IO_BRIDGE_mReadReg(XPAR_IO_BRIDGE_0_S00_AXI_BASEADDR, IO_BRIDGE_S00_AXI_SLV_REG3_OFFSET);
```

To print data to a PC, use the following functions:

```
#include "xil_printf.h"

// simple print to terminal
print("Welcome!\r\n");

// print variable value to terminal
xil_printf("result: %0x\r\n", axi_data);
```

View terminal output by opening a "Terminal" view in the SDK. To open a "Terminal" view in the SDK, follow the instructions on page 27 of [3].

Part III

Project Status

Quick Note

As of June 16, 2018, the MISST system core is partly implemented. The following sections describe which features are implemented, and which are not. The source code for each module also list needed features.

2.7 The ALU

The ALU is functionally complete, however, its random functions could be expanded. As of now, if the ALU was used in a complete MISST system, the system would function. The following additions will broaden the types of errors the ALU can produce.

- Expand random number generation from 16-bit output to 32-bit output. The module used for random number generation, `noise_gen`, uses a linear feedback shift register implementation to produce random value with four probability distributions. Due to `noise_gen`'s implementation, expansion to 32-bit output will be challenging if not impossible.
- Add functions that mimic single event upsets (a single bit is inverted in a group of data). The current single bit inversion operation only inverts a single bit within the least significant byte of operand A. Maybe expand this to within four bytes, or a byte other than the least significant byte.
- Add random number generator with Poisson distribution.
- Include random number generator with distribution specific parameters like average, variance, etc. Such a random number generator would produce random variables with a selected probability distribution and associated parameters.

2.8 Fault Parameters

The Fault Parameters module is complete. I don't see why Fault Parameters would have to be expanded, unless future developers deem it necessary to add another fault parameter.

2.9 The Control Unit

The Control Unit consists of three modules and three cycle counter modules. The three main modules are the register controller, the memory interconnect, and the injection campaign FSM (ICF). In summary:

- The register controller processes data between MISST system core and Adapter module.
- The memory interconnect contains MISST system registers and forwards data to the Fault Parameter module.
- ICF is the brains of the MISST system coordinating signals necessary for injection and sampling operations to be carried out properly.

The register controller and memory interconnect are complete. If any more registers are added to the MISST system, then memory interconnect would have to be updated accordingly.

The ICF is not complete. The injection process and shutdown check have not been implemented. The sampling process, however, has been implemented. The shutdown check refers to the ICF stopping the fault campaign when the number of sets has reached the maximum value. The steps in an injection process are outlined in the **Task Flow** section of the Design Guide.

2.10 Adapter Module

There is currently no Adapter module implementation, but how it will function, the ports needed, and development steps are known. The plan is outlined below.

1. Create an AXI-Lite peripheral IP core in Vivado. Vivado automatically generates a template that includes AXI-Lite protocol logic. All the user needs to do is add their logic. Section 2.6.2 goes over how to accomplish this.
2. Test AXI slave. I don't know how to test an AXI interface so I'd recommend testing the logic you implemented by making sure the AXI registers are written and read from properly. *Do not heavily modify the AXI-Lite protocol logic..* If you do, you might need to test the AXI interface itself which I'm not sure how to do.
3. Package AXI-slave IP.
4. Open a new Vivado project and create a block design. In this block design connect the PYNQ's hard processor, the PYNQ processor system, to the AXI slave (which should be connected to MISST), and the DUT (along with whatever interfaces needed). The ultimate goal of this step is to generate the bit-stream of the block design. See section 2.6.3 for instructions.
5. Export the bit-stream to the SDK (Software Development Kit) to program the hard processor. Refer to **Role of Cortex Processor** section of Design Guide for processor behavior.
6. Program the FPGA, and then program the hard processor.
7. Setup MISST registers through the PC, and start fault campaign when ready.

2.11 Module Verification

I consider a feature implemented if it has been simulated and verified to function as planned. All previously mentioned features have been tested and verified to work. However, these tests are unit tests. I haven't tested if the submodules of the Control Unit function *together*. So when I say that the sampling process has been implemented for the ICF, I mean that the ICF can carry out its role in the sampling process i.e. turn on and off the ICF ports in the correct sequence to read data from the DUT.

2.12 Suggested Target DUT

When the MISST system core and Adapter module are implemented, I suggest the following target systems.

- LEON3: An open source 32-bit microprocessor core. The LEON3 is well documented and configurable, and its VHDL source code is available online. Source code, dependencies, and instructions on implementing the LEON3 processor can be found at [6].
- MIAOW: Acronym for Many-core Integrated Accelerator Of Waterdeep/Wisconsin, is the only open source GPU freely available online. Note that the MIAOW requires roughly four times as many look-up tables as the ZYNQ FPGA has available. So to test on MIAOW must be implemented on a larger FPGA. Information about MIAOW can be found at [7].

Bibliography

- [1] 'Why the library "numeric_std" is preferred over "std_logic_arith" and others', 2010. [Online]. Available: <http://vhdlguru.blogspot.com/2010/03/why-library-numericstd-is-preferred.html>. [Accessed: 5 April 2018].
- [2] PYNQ-Z1 Board Reference Manual. (2018). [ebook] Pullman. Available at: https://reference.digilentinc.com/_media/reference/programmable-logic/pynq-z1/pynq-rm.pdf [Accessed: 24 Feb. 2018].
- [3] Zynq-7000 All Programmable SoC: Embedded Design Tutorial. (2015). [ebook]. Available at: https://www.xilinx.com/support/documentation/sw_manuals/xilinx2015_1/ug1165-zynq-embedded-design-tutorial.pdf [Accessed: 6 May 2018].
- [4] PYNQ-Z1. [Online]. Available: <https://reference.digilentinc.com/reference/programmable-logic/pynq-z1/start> [Accessed: 6 May 2018].
- [5] Vivado Design Suite User Guide Creating and Packaging Custom IP. (2015). [ebook]. Available at: https://www.xilinx.com/support/documentation/sw_manuals/xilinx2017_2/ug1118-vivado-creating-packaging-custom-ip.pdf [Accessed: April 8, 2018].
- [6] 'LEON3 Processor', [Online]. Available: <https://www.gaisler.com/index.php/products/processors/leon3>
- [7] 'MIAOW GPU', [Online]. Available: <http://miaowgpu.org/>